



SLOVENSKI STANDARD

oSIST prEN ISO 16526-2:2019

01-november-2019

Neporušitvene preiskave - Meritve in ugotavljanje električne napetosti na rentgenski cevi - 2. del: Preverjanje konstantnosti z metodo debelega filtra (ISO 16526-2:2011)

Non-destructive testing - Measurement and evaluation of the X-ray tube voltage - Part 2: Constancy check by the thick filter method (ISO 16526-2:2011)

Zerstörungsfreie Prüfung - Messung und Auswertung der Röntgenröhrenspannung - Teil 2: Konstanzprüfung mit dem Dickfilter-Verfahren (ISO 16526-2:2011)

Essais non destructifs - Mesurage et évaluation de la tension des tubes radiogènes - Partie 2: Contrôle de la constance selon la méthode du filtre épais (ISO 16526-2:2011)

Ta slovenski standard je istoveten z: prEN ISO 16526-2

ICS:

19.100 Neporušitveno preskušanje Non-destructive testing

oSIST prEN ISO 16526-2:2019

en,fr,de

INTERNATIONAL STANDARD

ISO
16526-2

First edition
2011-12-15

Non-destructive testing — Measurement and evaluation of the X-ray tube voltage —

Part 2: Constancy check by the thick filter method

*Essais non destructifs — Mesurage et évaluation de la tension des
tubes radiogènes —*

Partie 2: Contrôle de la constance selon la méthode du filtre épais

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Reference number
ISO 16526-2:2011(E)

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Published in Switzerland

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 16526-2 was prepared by CEN (as EN 12544-2:2000) and is submitted for approval under a special “fast-track procedure”, by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 5, *Radiation methods*, in parallel with its approval by the ISO member bodies (see the *ISO/IEC Directives*, Part 1, “Fast-track procedure”).

ISO 16526 consists of the following parts, under the general title *Non-destructive testing — Measurement and evaluation of the X-ray tube voltage*:

- *Part 1: Voltage divider method* [SIST EN ISO 16526-2:2020](https://standards.iteh.ai/catalog/standards/sist/c9c7d6cd-b817-4d21-a4ff-f8c36487d409/sist-16526-2-2020)
- *Part 2: Constancy check by the thick filter method* [16526-2-2020](https://standards.iteh.ai/catalog/standards/sist/c9c7d6cd-b817-4d21-a4ff-f8c36487d409/sist-16526-2-2020)
- *Part 3: Spectrometric method*

Introduction

In order to cover the different requirements for the measurement of the X-ray tube voltage, three different methods are described in ISO 16526-1 to ISO 16526-3.

The voltage divider method (ISO 16526-1) enables a direct and absolute measurement of the average high voltage of constant potential X-ray systems on the secondary side of the high voltage generator.

The thick filter method (ISO 16526-2) describes a constancy check. This method is recommended for the regular stability check of an X-ray system.

The spectrometric method (ISO 16526-3) is a procedure for non-invasive measurement of the X-ray tube voltage using the energy spectrum of the X-rays. This method can be applied for all X-ray systems and shall be applied whenever the voltage divider method is not applicable, e. g. in case of tank units where it is not possible to connect the voltage divider device.

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Non-destructive testing — Measurement and evaluation of the X-ray tube voltage —

Part 2: Constancy check by the thick filter method

1 Scope

This part of ISO 16526 specifies a constancy check of a X-ray system where mainly the X-ray voltage is checked as a function of the tube current and the constitution of the target which can be changing due to ageing of the tube.

The thick filter method is based on a measurement of the dose rate behind a defined thick filter using defined distances between the X-ray tube, the filter and the measuring device.

This method is very sensitive to changes of the voltage, but it does not provide an absolute value for the X-ray tube voltage. Therefore, a reference value is needed and, it is recommended to find this reference, for example, within the acceptance test of the system.

The thick filter method is a rather simple technique and may be applied by the operator of an X-ray system to perform regularly a constancy check of the system.

The method can also be applied for consistency checks after changing components which may affect the X-ray tube voltage.

This method can be applied for all types of X-ray systems, i. e. for constant potential, half wave and impulse wave generators with a tube current larger than 1 mA.

2 Principle and equipment

The equipment to be used includes the following components, see figure 1:

- the X-ray system;
- a specified collimator;
- a specified filter;
- suitable dose meter or dose rate meter;
- a film for the prove of good collimation and dose meter or dose rate meter adjustment.

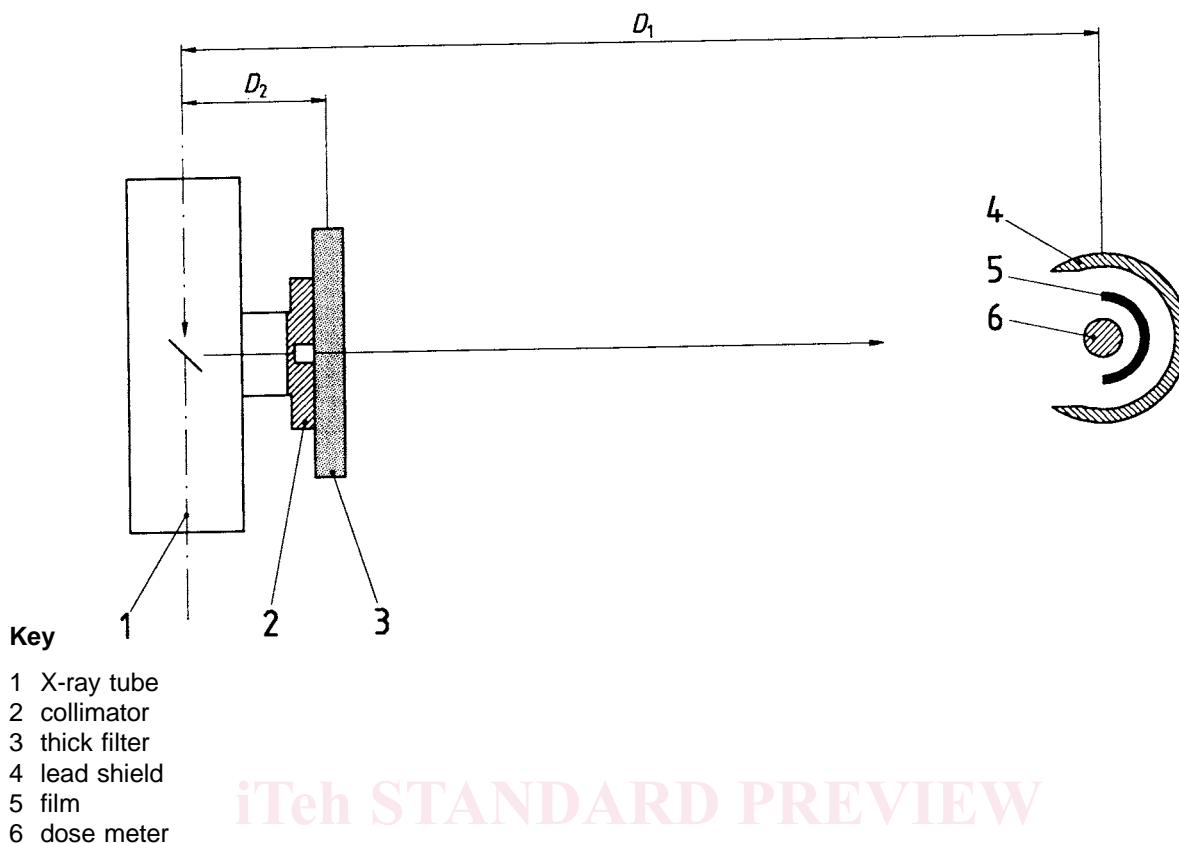


Figure 1 – Setup of the thick filter method

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It is possible to apply any type of filter and distances. Two aspects are important:

- To obtain reproducible values, the collimator, the filter and the dose rate meter shall be identical and, the focus to filter distance D_2 and the focus to dose rate meter distance D_1 shall be fixed for the reference and all subsequent measurements.
- The filter material and thickness shall be selected according to figure 2.

The requirements concerning the dose meter or dose rate meter are:

- The long term stability shall be 3 times better than the tolerance of the measured values. A regular stability check of the dose rate meter, using a radioactive source, is necessary.
- The device shall have adequate measuring ranges.
- The exposure time shall be selected to obtain values between 50 % and 100 % of the scale. Three or more measurements shall be taken and the results shall be averaged.

The diameter of the selected collimator shall be as small as possible. The area of homogeneous radiation intensity at the dose meter or dose rate meter shall be equal or less than 3 times of the size of the detection chamber of the dose meter. This shall be proven with a film exposure due to the requirement of exact adjustment. This radiograph marked with the date of measurement may be used for documentation. Figure 3 shows a typical radiograph of a dose meter which is well adjusted corresponding to figure 1.

NOTE : The results of the measurement arrangement are reliable if it provides the same value in horizontal and vertical adjustment.

Using the thick filter method, the measured values will change approximately 5 to 10 times faster (leverage factor) than the X-ray voltage changes. That means for example that 5 % of the X-ray tube voltage change corresponds to 25 % to 50 % of the measured dose rate.